AMENDMENT TRANSMITTAL LETTER (Small Entity) Applicant(s): Donald Malcolm MacIntyre					Docket No. MAI1003
I		g Date	Examiner D. Wille		Group Art Unit 2814
Invention: CHI	P SCALE PACKAGE	Sim Flushing			
	TO THE	ASSISTANT COMM	MISSIONER FOR PATE	:NTS:	
☒ Small En previousl☒ A verified	y submitted.	Small Entity status	olished under 37 CFR 1 under 37 FR 1.27 is end	·	rified statement
	10	CLAIMS AS	AMENDED		
	CLAIMS REMAINING AFTER AMENDMENT	HIGHEST # PREV. PAID FOR	NUMBER EXTRA CLAIMS PRESENT	RATE	ADDITIONAL FEE
TOTAL CLAIMS	6 -	20 =	0	x \$9.0	\$0.00
INDEP. CLAIMS	2 -	3 =	0	x \$39.	00 \$0 00
Multiple Dependent Claims (check if applicable)					\$0 00
TOTAL ADDITIONAL FEE FOR THIS AMENDMENT					\$0 00
☐ Please ch A duplica ☐ A check i ☐ The Com communi A duplica ☐ Any ☐ Any	cation or credit any ove te copy of this sheet is additional filing fees red patent application proce	No. enclosed. to cover the fi horized to charge pa rpayment to Deposi enclosed. quired under 37 C.F. essing fees under 3	.R. 1.16. 7 CFR 1.17.	fees assoc	iated with this
N. Ur	signature	(7C	Dated: 2/22/99		

H. Donald Nelson, Reg. No. 28,980

I certify that this document and fee is being deposited on 2/22/99 with the U.S. Postal Service as first class mail under 37 C.F.R. 1.8 and is addressed to the Assistant Commissioner for Patents, Washington, D.C. 20231



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:

Donald Malcolm MacIntyre

Assignee:

None

Title:

CHIP SCALE PACK

Serial No.:

. 09/045,507

Examiner:

D. Wille

Filed: 3/20/98

Group Art Unit: 2814

Attorney Docket No.:

MAI1003

San Jose, California February 22, 1999

COMMISSIONER OF PATENTS AND TRADEMARKS Washington, D.C. 20231

AMENDMENT

Sir:

In response to the Examiner's Office Action of 10/23/98, please amend the above-cited application as follows.

In the Specification

On page 1, line 16, please change "interconnect" to read - - interconnects - -.

On page 8, line 19, please change "300" to read - - 200 - -.

On page 8, line 20, please change "308" to read - - 208 - -.

In the Claims

Please amend the claims as follows. For the convenience of the Examiner, claims not amended are reproduced below in reduced font.

Please cancel Claims 1, 2, and 3 and substitute new Claim 15 therefor.

-- 15. (New) A chip scale structure comprising:

a semiconductor wafer with a pattern of bond pads on a surface of the semiconductor wafer, wherein the bond pads can be formed anywhere on the surface of the semiconductor wafer:

a glass sheet with holes $m \cdot a$ pattern matching the pattern of bond pads on the surface of the semiconductor wafer:

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